



Welcome to [E-XFL.COM](https://www.e-xfl.com)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	80
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	80K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc56ap60l5cefar

List of figures

Figure 1.	SPC56xP54x/SPC56xP60x block diagram	11
Figure 2.	LQFP176 pinout (top view)	27
Figure 3.	LQFP144 pinout (top view)	28
Figure 4.	LQFP100 pinout (top view)	29
Figure 5.	Power supplies constraints	50
Figure 6.	Independent ADC supply	51
Figure 7.	Power supplies constraints	54
Figure 8.	Independent ADC supply	55
Figure 9.	Voltage regulator configuration	59
Figure 10.	Power-up typical sequence	62
Figure 11.	Power-down typical sequence	62
Figure 12.	Brown-out typical sequence	63
Figure 13.	I/O input DC electrical characteristics definition	64
Figure 14.	I/O input DC electrical characteristics definition	67
Figure 15.	ADC characteristics and error definitions	75
Figure 16.	Input equivalent circuit (precise channels)	76
Figure 17.	Input equivalent circuit (extended channels)	77
Figure 18.	Transient behavior during sampling phase	77
Figure 19.	Spectral representation of input signal	79
Figure 20.	Start-up reset requirements	84
Figure 21.	Noise filtering on reset signal	84
Figure 22.	JTAG test clock input timing	86
Figure 23.	JTAG test access port timing	87
Figure 24.	JTAG boundary scan timing	88
Figure 25.	Nexus output timing	89
Figure 26.	Nexus event trigger and test clock timings	89
Figure 27.	Nexus TDI, TMS, TDO timing	90
Figure 28.	External interrupt timing	91
Figure 29.	DSPI classic SPI timing — master, CPHA = 0	92
Figure 30.	DSPI classic SPI timing — master, CPHA = 1	93
Figure 31.	DSPI classic SPI timing — slave, CPHA = 0	93
Figure 32.	DSPI classic SPI timing — slave, CPHA = 1	94
Figure 33.	DSPI modified transfer format timing — master, CPHA = 0	94
Figure 34.	DSPI modified transfer format timing — master, CPHA = 1	95
Figure 35.	DSPI modified transfer format timing — slave, CPHA = 0	95
Figure 36.	DSPI modified transfer format timing — slave, CPHA = 1	96
Figure 37.	DSPI PCS strobe (PCSS) timing	96
Figure 38.	LQFP144 package mechanical drawing	97
Figure 39.	LQFP100 package mechanical drawing	99
Figure 40.	Ordering information scheme	101

SPC56xP54x/SPC56xP60x is present on the market in two different options enabling different features: Full-featured, and Airbag configuration. [Table 3](#) shows the main differences between the two versions.

Table 3. SPC56xP54x/SPC56xP60x device configuration difference

Feature	Enhanced Full-featured	Full-featured	Airbag
FlexCAN (controller area network)	3	2	2
CTU (cross triggering unit)	Yes		No
FlexRay	Yes (64 message buffer)		No
DSPI (deserial serial peripheral interface) modules	5		4
CRC (cyclic redundancy check) unit	2		1

1.4 Block diagram

[Figure 1](#) shows a top-level block diagram of the SPC56xP54x/SPC56xP60x MCU. [Table 4](#) summarizes the functions of the blocks.

1.5.13 Software watchdog timer (SWT)

The SWT has the following features:

- Fault tolerant output
- Safe internal RC oscillator as reference clock
- Windowed watchdog
- Program flow control monitor with 16-bit pseudorandom key generation

The SWT module is replicated for each processor.

1.5.14 Fault collection and control unit (FCCU)

The FCCU provides an independent fault reporting mechanism even if the CPU is exhibiting unstable behaviors. The FCCU module has the following features:

- Redundant collection of hardware checker results
- Redundant collection of error information and latch of faults from critical modules on the device
- Collection of self-test results
- Configurable and graded fault control
 - Internal reactions (no internal reaction, IRQ)
 - External reaction (failure is reported to the external/surrounding system via configurable output pins)

1.5.15 System integration unit (SIUL)

The SPC56xP54x/SPC56xP60x SIUL controls MCU pad configuration, external interrupts, general purpose I/O (GPIO) pin configuration, and internal peripheral multiplexing.

The pad configuration block controls the static electrical characteristics of I/O pins. The GPIO block provides uniform and discrete input/output control of the I/O pins of the MCU.

The SIUL provides the following features:

- Centralized general purpose input output (GPIO) control of input/output pins and analog input-only pads (package dependent)
- All GPIO pins can be independently configured to support pull-up, pull down, or no pull
- Reading and writing to GPIO supported both as individual pins and 16-bit wide ports
- All peripheral pins (except ADC channels) can be alternatively configured as both general purpose input or output pins
- ADC channels support alternative configuration as general purpose inputs
- Direct readback of the pin value is supported on all pins through the SIU
- Configurable digital input filter that can be applied to some general purpose input pins for noise elimination
 - Up to 4 internal functions can be multiplexed onto one pin

1.5.16 Boot and censorship

Different booting modes are available in the SPC56xP54x/SPC56xP60x:

- From internal flash memory
- Via a serial link

1.5.21 Serial communication interface module (LINFlex)

The LINFlex on the SPC56xP54x/SPC56xP60x features the following:

- Supports LIN Master mode (on both modules), LIN Slave mode (on one module) and UART mode
- LIN state machine compliant to LIN1.3, 2.0, and 2.1 Specifications
- Handles LIN frame transmission and reception without CPU intervention
- LIN features
 - Autonomous LIN frame handling
 - Message buffer to store Identifier and up to 8 data bytes
 - Supports message length as long as 64 bytes
 - Detection and flagging of LIN errors: Sync field; Delimiter; ID parity; Bit; Framing; Checksum and Time-out errors
 - Classic or extended checksum calculation
 - Configurable Break duration as long as 36-bit times
 - Programmable Baud rate prescalers (13-bit mantissa, 4-bit fractional)
 - Diagnostic features: Loop back; Self Test; LIN bus stuck dominant detection
 - Interrupt-driven operation with 16 interrupt sources
- LIN slave mode features
 - Autonomous LIN header handling
 - Autonomous LIN response handling
- UART mode
 - Full-duplex operation
 - Standard non return-to-zero (NRZ) mark/space format
 - Data buffers with 4-byte receive, 4-byte transmit
 - Configurable word length (8-bit or 9-bit words)
 - Error detection and flagging
 - Parity, Noise and Framing errors
 - Interrupt-driven operation with four interrupt sources
 - Separate transmitter and receiver CPU interrupt sources
 - 16-bit programmable baud-rate modulus counter and 16-bit fractional
 - 2 receiver wake-up methods

1.5.22 Deserial serial peripheral interface (DSPI)

The deserial serial peripheral interface (DSPI) module provides a synchronous serial interface for communication between the SPC56xP54x/SPC56xP60x MCU and external devices.

- Watchpoint triggering, watchpoint triggers program tracing
 - DDR
- Auxiliary Output Port
 - 4 MDO (Message Data Out) pins
 - MCKO (Message Clock Out) pin
 - 2 $\overline{\text{MSEO}}$ (Message Start/End Out) pins
 - $\overline{\text{EVTO}}$ (Event Out) pin
- Auxiliary Input Port
 - $\overline{\text{EVTI}}$ (Event In) pin^(a)

1.5.28 IEEE 1149.1 (JTAG) controller

The JTAG controller (JTAGC) block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

The JTAG controller provides the following features:

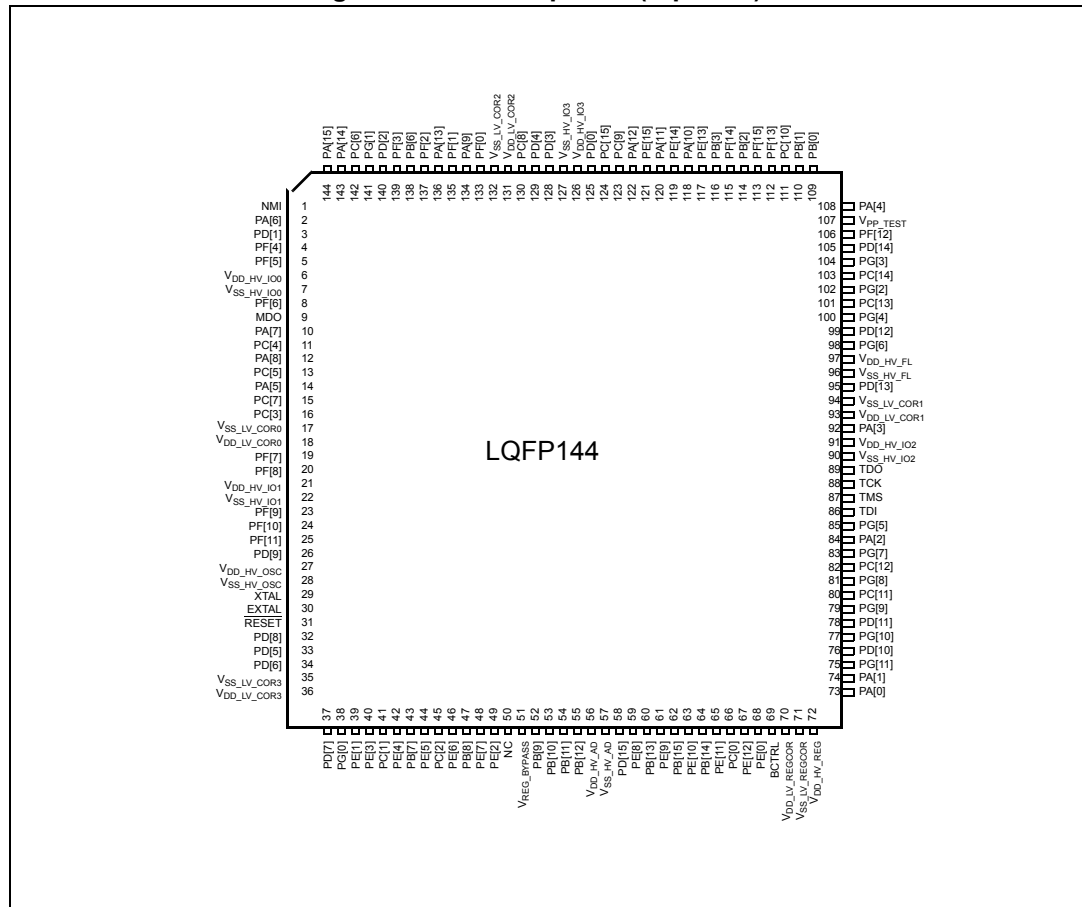
- IEEE Test Access Port (TAP) interface with four pins (TDI, TMS, TCK, TDO)
- Selectable modes of operation include JTAGC/debug or normal system operation.
- A 5-bit instruction register that supports the following IEEE 1149.1-2001 defined instructions:
 - BYPASS, IDCODE, EXTEST, SAMPLE, SAMPLE/PRELOAD
- A 5-bit instruction register that supports the additional following public instructions:
 - ACCESS_AUX_TAP_NPC, ACCESS_AUX_TAP_CORE0, ACCESS_AUX_TAP_CORE1, ACCESS_AUX_TAP_NASPS_0, ACCESS_AUX_TAP_NASPS_1
- Three test data registers: a bypass register, a boundary scan register, and a device identification register.
- A TAP controller state machine that controls the operation of the data registers, instruction register and associated circuitry.

1.5.29 On-chip voltage regulator (VREG)

The on-chip voltage regulator module provides the following features:

- Uses external NPN transistor
- Regulates external 3.3 V to 5.0 V down to 1.2 V for the core logic
- Low voltage detection on the internal 1.2 V and I/O voltage 3.3 V

a. At least one TCK clock is necessary for the EVTI signal to be recognized by the MCU.

Figure 3. LQFP144 pinout (top view)^(c)

c. Availability of port pin alternate functions depends on product selection.

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ⁽²⁾ , (3)	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
E[7]	PCR[71]	ALT0 ALT1 ALT2 ALT3 —	GPIO[71] — — — AN[10]	SIUL — — — ADC_0	Input Only	—	—	—	48	56
E[8]	PCR[72]	ALT0 ALT1 ALT2 ALT3 —	GPIO[72] — — — AN[22]	SIUL — — — ADC_0	Input Only	—	—	—	59	67
E[9]	PCR[73]	ALT0 ALT1 ALT2 ALT3 —	GPIO[73] — — — AN[23]	SIUL — — — ADC_0	Input Only	—	—	—	61	69
E[10]	PCR[74]	ALT0 ALT1 ALT2 ALT3 —	GPIO[74] — — — AN[24]	SIUL — — — ADC_0	Input Only	—	—	—	63	75
E[11]	PCR[75]	ALT0 ALT1 ALT2 ALT3 —	GPIO[75] — — — AN[25]	SIUL — — — ADC_0	Input Only	—	—	—	65	77
E[12]	PCR[76]	ALT0 ALT1 ALT2 ALT3 —	GPIO[76] — — — AN[26]	SIUL — — — ADC_0	Input Only	—	—	—	67	79
E[13]	PCR[77]	ALT0 ALT1 ALT2 ALT3 —	GPIO[77] SCK_3 — — EIRQ[25]	SIUL DSPI_3 — — SIUL	I/O I/O — — I	Slow	Medium	—	117	141
E[14]	PCR[78]	ALT0 ALT1 ALT2 ALT3 —	GPIO[78] SOUT_3 — — EIRQ[26]	SIUL DSPI_3 — — SIUL	I/O O — — I	Slow	Medium	—	119	143

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ^{(2), (3)}	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
E[15]	PCR[79]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[79] — — — SIN_3 EIRQ[27]	SIUL — — — DSPI_3 SIUL	I/O — — — I I	Slow	Medium	—	121	145
Port F										
F[0]	PCR[80]	ALT0 ALT1 ALT2 ALT3 —	GPIO[80] DBG_0 CS3_3 — EIRQ[28]	SIUL FlexRay_0 DSPI_3 — SIUL	I/O O O — I	Slow	Medium	—	133	157
F[1]	PCR[81]	ALT0 ALT1 ALT2 ALT3 —	GPIO[81] DBG_1 CS2_3 — EIRQ[29]	SIUL FlexRay_0 DSPI_3 — SIUL	I/O O O — I	Slow	Medium	—	135	159
F[2]	PCR[82]	ALT0 ALT1 ALT2 ALT3	GPIO[82] DBG_2 CS1_3 —	SIUL FlexRay_0 DSPI_3 —	I/O O O —	Slow	Medium	—	137	161
F[3]	PCR[83]	ALT0 ALT1 ALT2 ALT3	GPIO[83] DBG_3 CS0_3 —	SIUL FlexRay_0 DSPI_3 —	I/O O I/O —	Slow	Medium	—	139	167
F[4]	PCR[84]	ALT0 ALT1 ALT2 ALT3	— — MDO[3] —	— — nexus_0 —	— — O —	Slow	Fast	—	4	4
F[5]	PCR[85]	ALT0 ALT1 ALT2 ALT3	— — MDO[2] —	— — nexus_0 —	— — O —	Slow	Fast	—	5	13
F[6]	PCR[86]	ALT0 ALT1 ALT2 ALT3	GPIO[86] — MDO[1] —	SIUL — nexus_0 —	I/O — O —	Slow	Fast	—	8	16

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ⁽²⁾ , (3)	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
F[7]	PCR[87]	ALT0 ALT1 ALT2 ALT3	GPIO[87] — MCKO —	SIUL — nexus_0 —	I/O — O —	Slow	Fast	—	19	27
F[8]	PCR[88]	ALT0 ALT1 ALT2 ALT3	GPIO[88] — MSEO1 —	SIUL — nexus_0 —	I/O — O —	Slow	Fast	—	20	28
F[9]	PCR[89]	ALT0 ALT1 ALT2 ALT3	GPIO[89] — MSEO0 —	SIUL — nexus_0 —	I/O — O —	Slow	Fast	—	23	31
F[10]	PCR[90]	ALT0 ALT1 ALT2 ALT3	GPIO[90] — EVTO —	SIUL — nexus_0 —	I/O — O —	Slow	Fast	—	24	32
F[11]	PCR[91]	ALT0 ALT1 ALT2 ALT3	GPIO[91] EVTI — —	SIUL nexus_0 — —	I/O I — —	Slow	Medium	—	25	33
F[12]	PCR[92]	ALT0 ALT1 ALT2 ALT3	GPIO[92] ETC[3] — —	SIUL eTimer_1 — —	I/O I/O — —	Slow	Medium	—	106	130
F[13]	PCR[93]	ALT0 ALT1 ALT2 ALT3	GPIO[93] ETC[4] — —	SIUL eTimer_1 — —	I/O I/O — —	Slow	Medium	—	112	136
F[14]	PCR[94]	ALT0 ALT1 ALT2 ALT3	GPIO[94] TXD — —	SIUL LINFlex_1 — —	I/O O — —	Slow	Medium	—	115	139
F[15]	PCR[95]	ALT0 ALT1 ALT2 ALT3 —	GPIO[95] — — — RXD	SIUL — — — LINFlex_1	I/O — — — I	Slow	Medium	—	113	137

Table 7. Pin muxing⁽¹⁾ (continued)

Port pin	PCR No.	Alternate function ⁽²⁾ , (3)	Functions	Peripheral ⁽⁴⁾	I/O direction ⁽⁵⁾	Pad speed ⁽⁶⁾		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176 ⁽⁷⁾
G[8]	PCR[104]	ALT0 ALT1 ALT2 ALT3 —	GPIO[104] — CS3_4 —	SIUL — DSPI_4 —	I/O — O —	Slow	Medium	—	81	97
G[9]	PCR[105]	ALT0 ALT1 ALT2 ALT3 —	GPIO[105] — — — RXD	SIUL — — — FlexCAN_1	I/O — — — I	Slow	Medium	—	79	95
G[10]	PCR[106]	ALT0 ALT1 ALT2 ALT3	GPIO[106] — TXD —	SIUL — FlexCAN_1 —	I/O — O —	Slow	Medium	—	77	93
G[11]	PCR[107]	ALT0 ALT1 ALT2 ALT3	GPIO[107] — — — —	SIUL — — — —	I/O — — — —	Slow	Medium	—	75	91

1. This table concerns Enhanced Full-featured version. Please refer to "SPC56xP54x/SPC56xP60x device configuration difference" table for difference between Enhanced Full-featured, Full-featured, and Airbag configuration.
2. ALT0 is the primary (default) function for each port after reset.
3. Alternate functions are chosen by setting the values of the PCR[PA] bitfields inside the SIU module. PCR[PA] = 00 → ALT0; PCR[PA] = 01 → ALT1; PCR[PA] = 10 → ALT2; PCR[PA] = 11 → ALT3. This is intended to select the output functions; to use one of the input-only functions, the PCR[IBE] bit must be written to '1', regardless of the values selected in the PCR[PA] bitfields. For this reason, the value corresponding to an input only function is reported as "—".
4. Module included on the MCU.
5. Multiple inputs are routed to all respective modules internally. The input of some modules must be configured by setting the values of the PSMI[PADESELx] bitfields inside the SIUL module.
6. Programmable via the SRC (Slew Rate Control) bits in the respective Pad Configuration Register.
7. LQFP176 available only as development package.
8. Weak pull down during reset.

3.11 DC electrical characteristics

3.11.1 DC electrical characteristics (5 V)

Table 20 gives the DC electrical characteristics at 5 V ($4.5\text{ V} < V_{DD_HV_IOx} < 5.5\text{ V}$, $NVUSRO[PAD3V5V]=0$) as described in Figure 13.

Figure 13. I/O input DC electrical characteristics definition

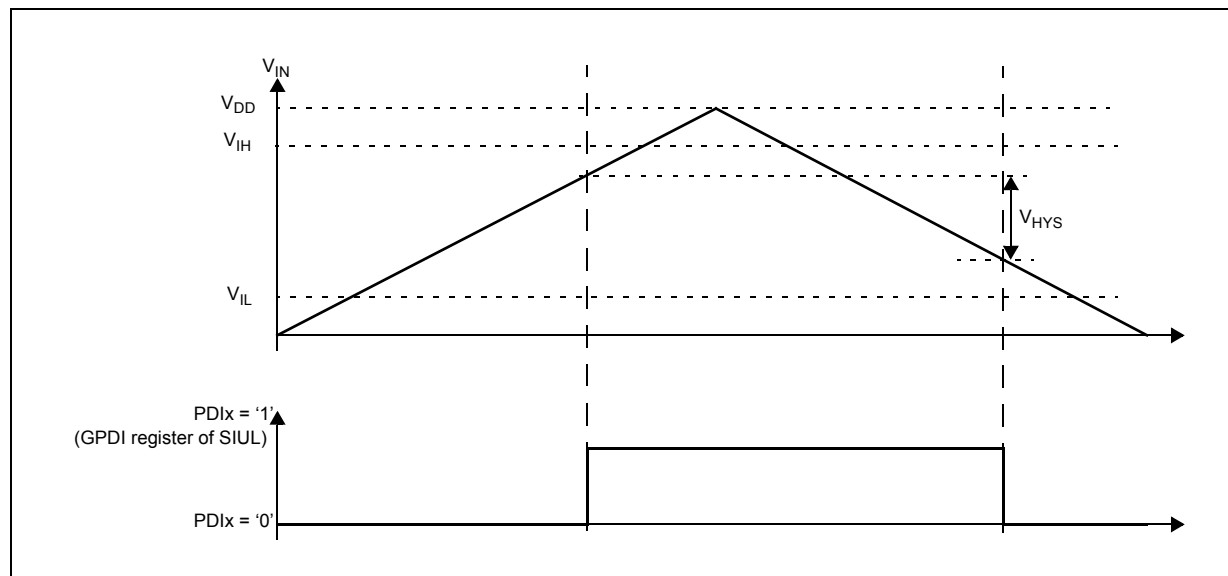


Table 20. DC electrical characteristics (5.0 V, $NVUSRO[PAD3V5V]=0$)

Symbol		Parameter	Conditions	Min	Max	Unit
V_{IL}	D	Minimum low level input voltage	—	$-0.1^{(1)}$	—	V
V_{IL}	P	Maximum level input voltage	—	—	$0.35 V_{DD_HV_IOx}$	V
V_{IH}	P	Minimum high level input voltage	—	$0.65 V_{DD_HV_IOx}$	—	V
V_{IH}	D	Maximum high level input voltage	—	—	$V_{DD_HV_IOx} + 0.1^{(1)}$	V
V_{HYS}	T	Schmitt trigger hysteresis	—	$0.1 V_{DD_HV_IOx}$	—	V
V_{OL_S}	P	Slow, low level output voltage	$I_{OL} = 3\text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_S}	P	Slow, high level output voltage	$I_{OH} = -3\text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
V_{OL_M}	P	Medium, low level output voltage	$I_{OL} = 3\text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_M}	P	Medium, high level output voltage	$I_{OH} = -3\text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
V_{OL_F}	P	Fast, low level output voltage	$I_{OL} = 3\text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_F}	P	Fast, high level output voltage	$I_{OH} = -3\text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
V_{OL_SYM}	P	Symmetric, low level output voltage	$I_{OL} = 3\text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_SYM}	P	Symmetric, high level output voltage	$I_{OH} = -3\text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V

Table 21. Supply current (5.0 V, NVUSRO[PAD3V5V]=0)

Symbol		Parameter		Conditions		Value		Unit
						Typ	Max	
I _{DD_LV_CORE}	T	Supply current	RUN — Maximum Mode ⁽¹⁾	V _{DD_LV_CORE} externally forced at 1.3 V ADC Freq = 32 MHz PLL Freq = 64 MHz	64 MHz	90	120	mA
			RUN - Platform consumption, single core ⁽²⁾	V _{DD_LV_CORE} externally forced to 1.3V	16 MHz	21	37	
					40 MHz	35	55	
					64 MHz	48	72	
			RUN - Platform consumption, dual core ⁽³⁾		16 MHz	24	41	
					40 MHz	42	64	
	64 MHz				58	85		
	P		RUN — Maximum Mode ⁽⁴⁾	V _{DD_LV_CORE} externally forced at 1.3 V	64 MHz	85	113	
			HALT Mode ⁽⁵⁾	V _{DD_LV_CORE} externally forced at 1.3 V	—	5.5	15	
			STOP Mode ⁽⁶⁾	V _{DD_LV_CORE} externally forced at 1.3 V	—	4.5	13	
I _{DD_FLASH}	T	Flash memory supply current during read	V _{DD_HV_FL} at 5.0 V	—	—	14		
		Flash memory supply current during erase operation on 1 flash memory module	V _{DD_HV_FL} at 5.0 V	—	—	42		
I _{DD_ADC}	T	ADC supply current — Maximum Mode	V _{DD_HV_AD} at 5.0 V ADC Freq = 16 MHz	—	3	4		
I _{DD_OSC}	T	OSC supply current	V _{DD_OSC} at 5.0 V	8 MHz	2.6	3.2		

1. Maximum mode configuration: Code fetched from Flash executed by dual core, SIUL, PIT, ADC_0, eTimer_0/1, LINFlex_0/1, STM, INTC_0/1, DSPI_0/1/2/3/4, FlexCAN_0/1, FlexRay (static consumption), CRC_0/1, FCCU, SRAM enabled. I/O supply current excluded.
2. RAM, Code and Data Flash powered, code fetched from Flash executed by single core, all peripherals gated; IRC16MHz on, PLL64MHz OFF (except for code running at 64 MHz). Code is performing continuous data transfer from Flash to RAM.
3. RAM, Code and Data Flash powered, code fetched from Flash executed by dual core, all peripherals gated; IRC16MHz on, PLL64MHz OFF (except for code running at 64 MHz). Code is performing continuous data transfer from Flash to RAM.
4. Maximum mode configuration: Code fetched from RAM executed by dual core, SIUL, PIT, ADC_0, eTimer_0/1, LINFlex_0/1, STM, INTC_0/1, DSPI_0/1/2/3/4, FlexCAN_0/1, FlexRay (static consumption), CRC_0/1, FCCU, SRAM enabled. I/O supply current excluded.
5. HALT mode configuration, only for the "P" classification: Code Flash memory in low power mode, data Flash memory in power down mode, OSC/PLL are OFF, FIRC is ON, Core clock gated, all peripherals are disabled.
6. STOP mode configuration, only for the "P" classification: Code and data Flash memories in power down mode, OSC/PLL are OFF, FIRC is ON, Core clock gated, all peripherals are disabled.

Table 29. Input clock characteristics

Symbol		Parameter	Min	Typ	Max	Unit
f_{OSC}	SR	Oscillator frequency	4	—	40	MHz
f_{CLK}	SR	Frequency in bypass	—	—	64	MHz
t_{rCLK}	SR	Rise/fall time in bypass	—	—	1	ns
t_{DC}	SR	Duty cycle	47.5	50	52.5	%

3.13 FMPLL electrical characteristics

Table 30. PLLMRFM electrical specifications ($V_{DDPLL} = 1.08\text{ V to }1.32\text{ V}$, $V_{SS} = V_{SSPLL} = 0\text{ V}$, $T_A = T_L\text{ to }T_H$)

Symbol		Parameter		Conditions	Value		Unit
					min	max	
$f_{ref_crystal}$ f_{ref_ext}	D	PLL reference frequency range ⁽¹⁾		Crystal reference	4	40	MHz
f_{pll_in}	D	Phase detector input frequency range (after pre-divider)		—	4	16	MHz
$f_{FMPLLOUT}$	D	Clock frequency range in normal mode		—	4	120	MHz
f_{FREE}	P	Free running frequency		Measured using clock division — typically /16	20	150	MHz
f_{sys}	D	On-chip PLL frequency		—	16	64	MHz
t_{CYC}	D	System clock period		—	—	$1 / f_{sys}$	ns
f_{LORL} f_{LORH}	D	Loss of reference frequency window ⁽²⁾		Lower limit	1.6	3.7	MHz
				Upper limit	24	56	
f_{SCM}	D	Self-clocked mode frequency ^{(3),(4)}		—	20	150	MHz
C_{JITTER}	T	CLKOUT period jitter ^{(5),(6),(7),(8)}	Short-term jitter ⁽⁹⁾	f_{SYS} maximum	−4	4	% f_{CLKOUT}
			Long-term jitter (avg. over 2 ms interval)	$f_{PLLIN} = 16\text{ MHz}$ (resonator), f_{PLLCLK} at 64 MHz, 4000 cycles	—	10	ns
t_{pll}	D	PLL lock time ^{(10), (11)}		—	—	200	μs
t_{dc}	D	Duty cycle of reference		—	40	60	%
f_{LCK}	D	Frequency LOCK range		—	−6	6	% f_{sys}
f_{UL}	D	Frequency un-LOCK range		—	−18	18	% f_{sys}
f_{CS} f_{DS}	D	Modulation Depth		Center spread	±0.25	±4.0 ⁽¹²⁾	% f_{sys}
				Down Spread	−0.5	−8.0	
f_{MOD}	D	Modulation frequency ⁽¹³⁾		—	—	70	kHz

1. Considering operation with PLL not bypassed.

3.17 AC specifications

3.17.1 Pad AC specifications

Table 36. Output pin transition times

Symbol	C	Parameter	Conditions ⁽¹⁾	Value			Unit
				Min	Typ	Max	
T_{tr}	CC	Output transition time output pin ⁽²⁾ SLOW configuration	$C_L = 25\text{ pF}$	—	—	50	ns
			$C_L = 50\text{ pF}$	—	—	100	
			$C_L = 100\text{ pF}$	—	—	125	
			$C_L = 25\text{ pF}$	—	—	40	
			$C_L = 50\text{ pF}$	—	—	50	
			$C_L = 100\text{ pF}$	—	—	75	
T_{tr}	CC	Output transition time output pin ⁽²⁾ MEDIUM configuration	$C_L = 25\text{ pF}$	—	—	10	ns
			$C_L = 50\text{ pF}$	—	—	20	
			$C_L = 100\text{ pF}$	—	—	40	
			$C_L = 25\text{ pF}$	—	—	12	
			$C_L = 50\text{ pF}$	—	—	25	
			$C_L = 100\text{ pF}$	—	—	40	
T_{tr}	CC	Output transition time output pin ⁽²⁾ FAST configuration	$C_L = 25\text{ pF}$	—	—	4	ns
			$C_L = 50\text{ pF}$	—	—	6	
			$C_L = 100\text{ pF}$	—	—	12	
			$C_L = 25\text{ pF}$	—	—	4	
			$C_L = 50\text{ pF}$	—	—	7	
			$C_L = 100\text{ pF}$	—	—	12	
$T_{sim}^{(3)}$	CC	Symmetric, same drive strength between N and P transistor	$V_{DD} = 5.0\text{ V} \pm 10\%$, PAD3V5V = 0	—	—	4	ns
			$V_{DD} = 3.3\text{ V} \pm 10\%$, PAD3V5V = 1	—	—	5	

1. $V_{DD} = 3.3\text{ V} \pm 10\%$ / $5.0\text{ V} \pm 10\%$, $T_A = -40\text{ }^\circ\text{C}$ to $T_{A\text{ MAX}}$, unless otherwise specified.

2. C_L includes device and package capacitances ($C_{PKG} < 5\text{ pF}$).

3. Transition timing of both positive and negative slopes will differ maximum 50 %.

3.18 AC timing characteristics

3.18.1 RESET pin characteristics

The SPC56xP54x/SPC56xP60x implements a dedicated bidirectional RESET pin.

Table 39. Nexus debug port timing⁽¹⁾ (continued)

No.	Symbol		C	Parameter	Value			Unit
					Min	Typ	Max	
6	t_{NTDIS}	CC	D	TDI data setup time	6	—	—	ns
	t_{NTMSS}	CC	D	TMS data setup time	6	—	—	ns
7	t_{NTDIH}	CC	D	TDI data hold time	10	—	—	ns
	t_{NTMSH}	CC	D	TMS data hold time	10	—	—	ns
8	t_{TDOV}	CC	D	TCK low to TDO data valid	—	—	35	ns
9	t_{TDOI}	CC	D	TCK low to TDO data invalid	6	—	—	ns

1. All values need to be confirmed during device validation.
2. Lower frequency is required to be fully compliant to standard.

Figure 25. Nexus output timing

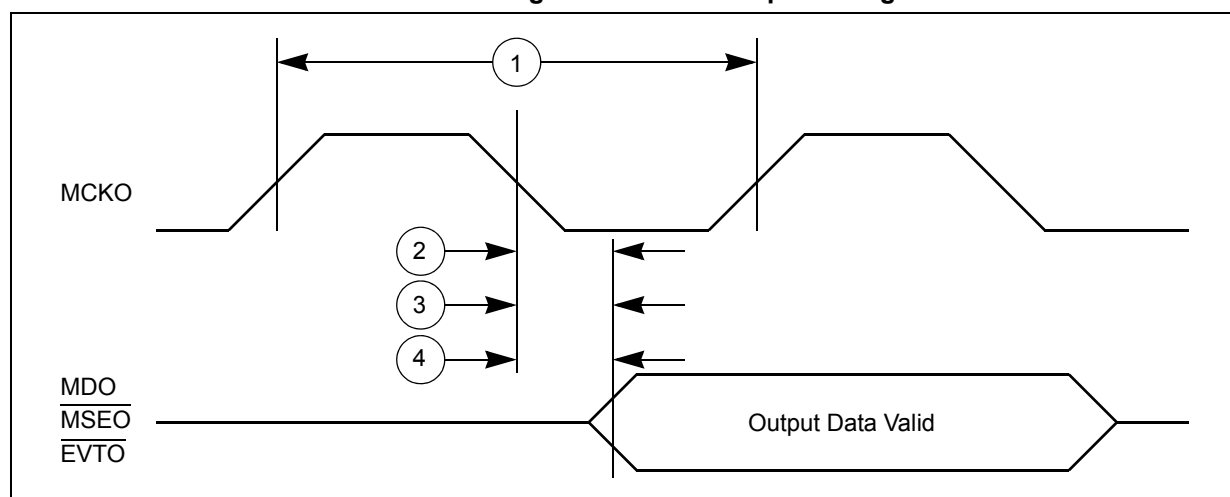


Figure 26. Nexus event trigger and test clock timings

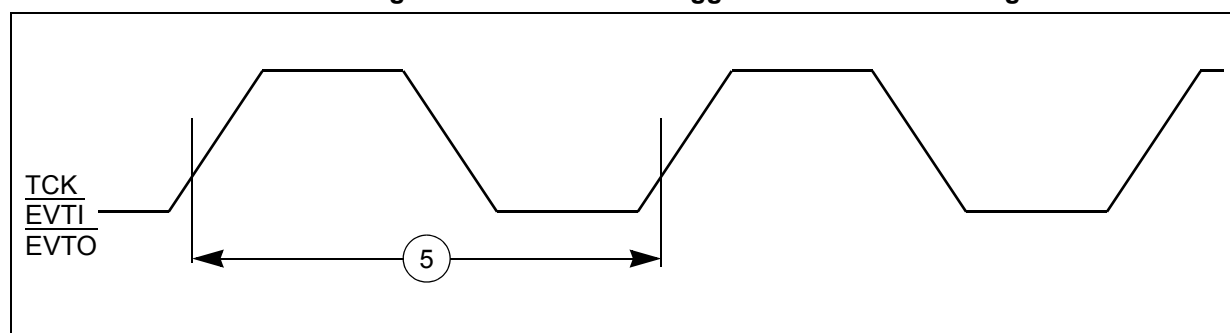


Table 41. DSPI timing⁽¹⁾ (continued)

No.	Symbol	C	D	Parameter	Conditions	Min	Max	Unit
12	t_{HO}	CC	D	Data hold time for outputs	Master (MTFE = 0)	-2	—	ns
					Slave	6	—	
					Master (MTFE = 1, CPHA = 0)	6	—	
					Master (MTFE = 1, CPHA = 1)	-2	—	

1. All timing are provided with 50pF capacitance on output, 1ns transition time on input signal

Figure 29. DSPI classic SPI timing — master, CPHA = 0

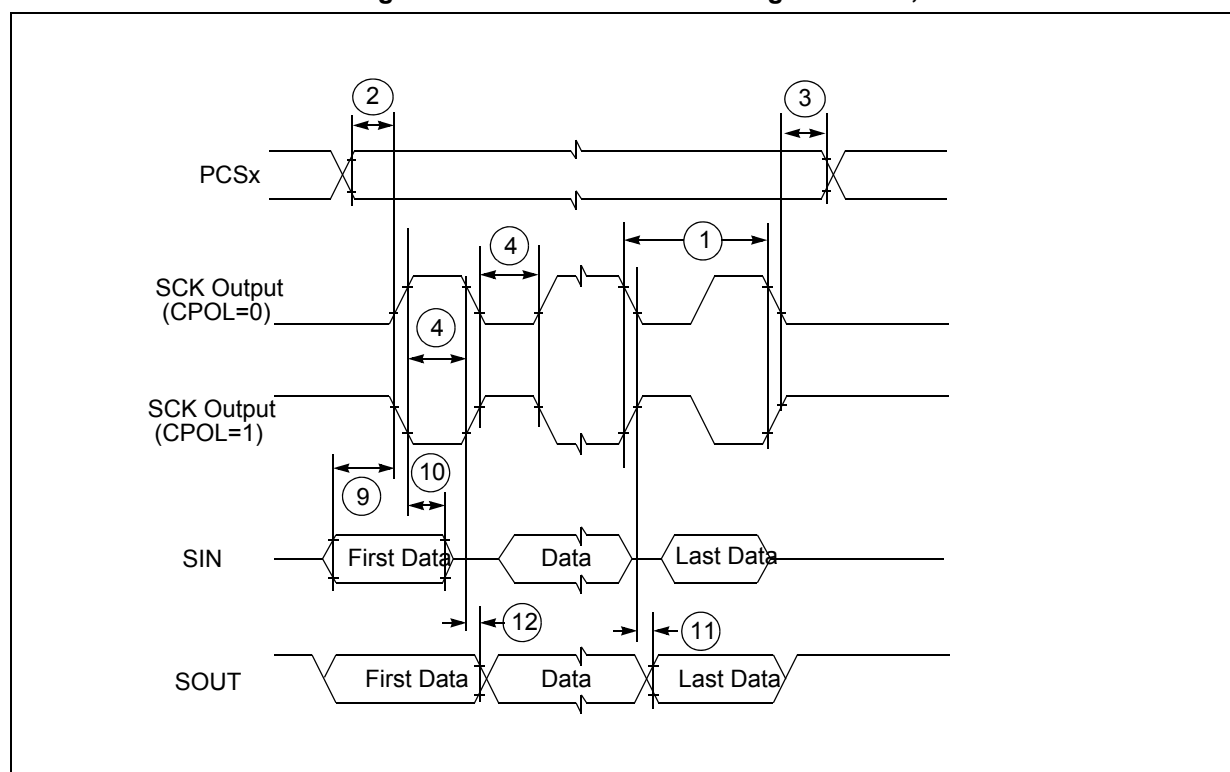


Figure 32. DSPI classic SPI timing — slave, CPHA = 1

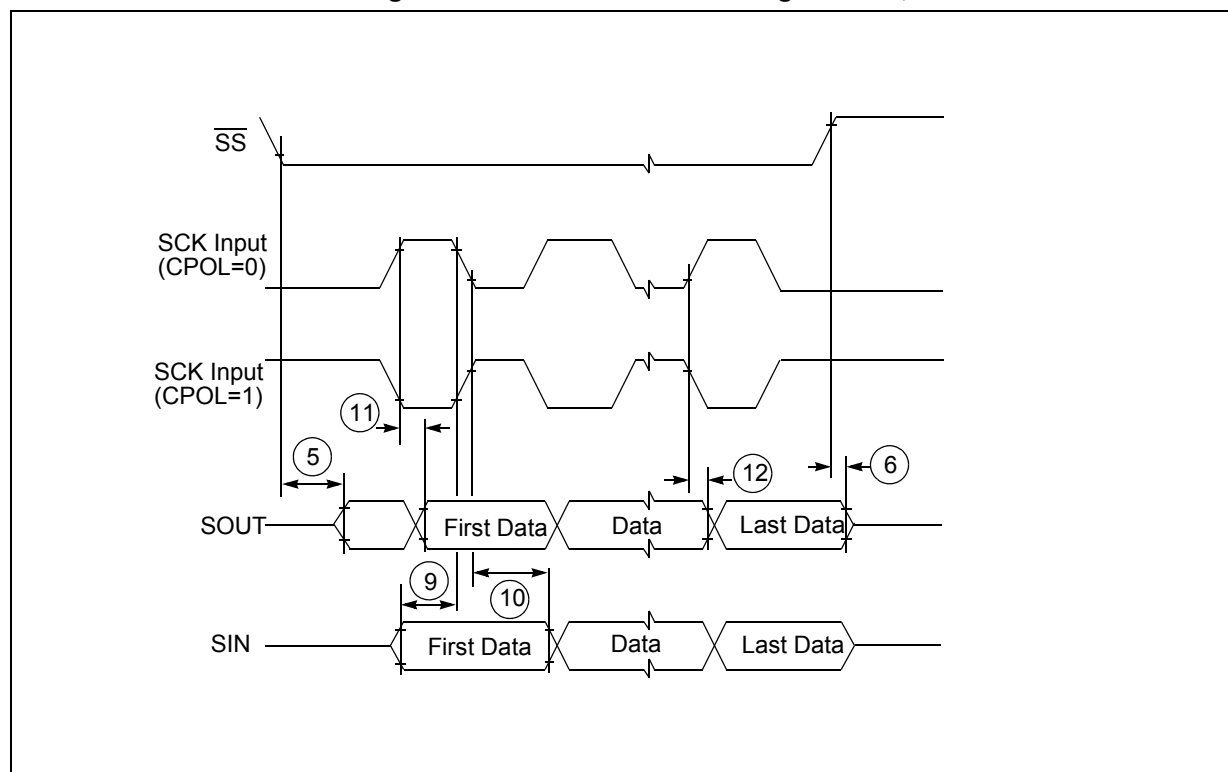


Figure 33. DSPI modified transfer format timing — master, CPHA = 0

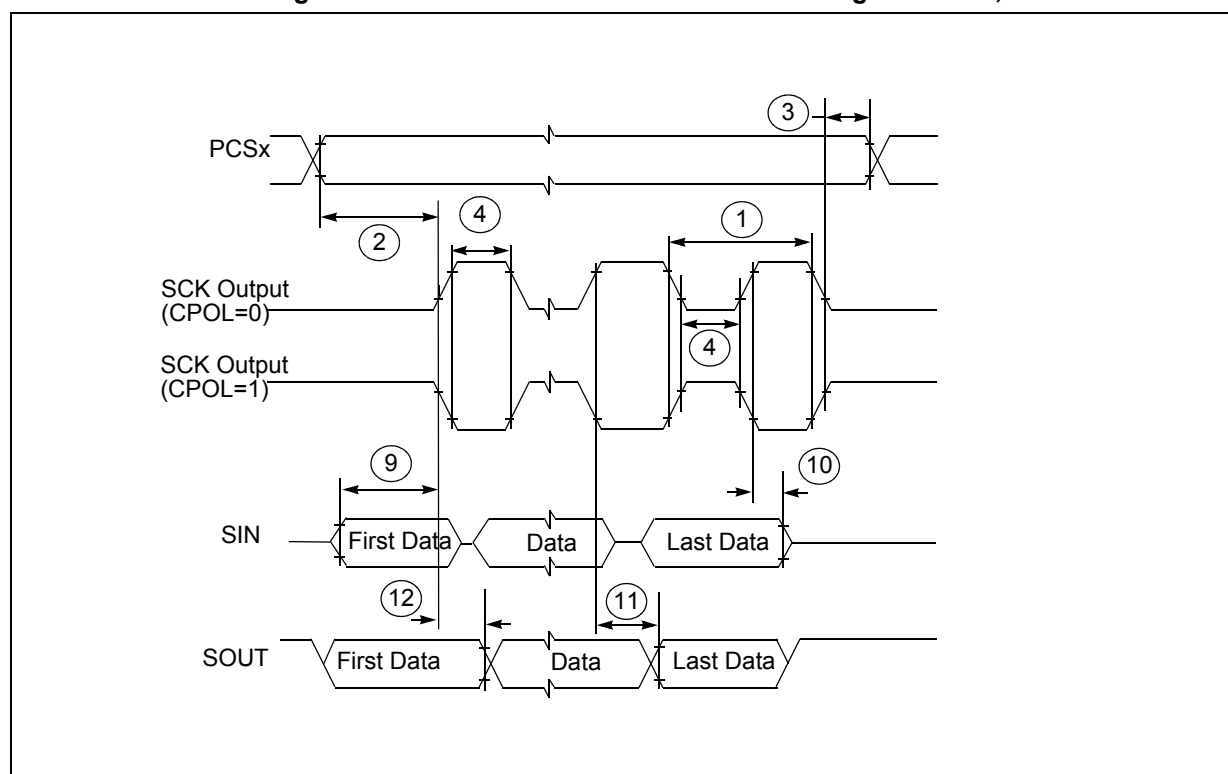


Figure 34. DSPI modified transfer format timing — master, CPHA = 1

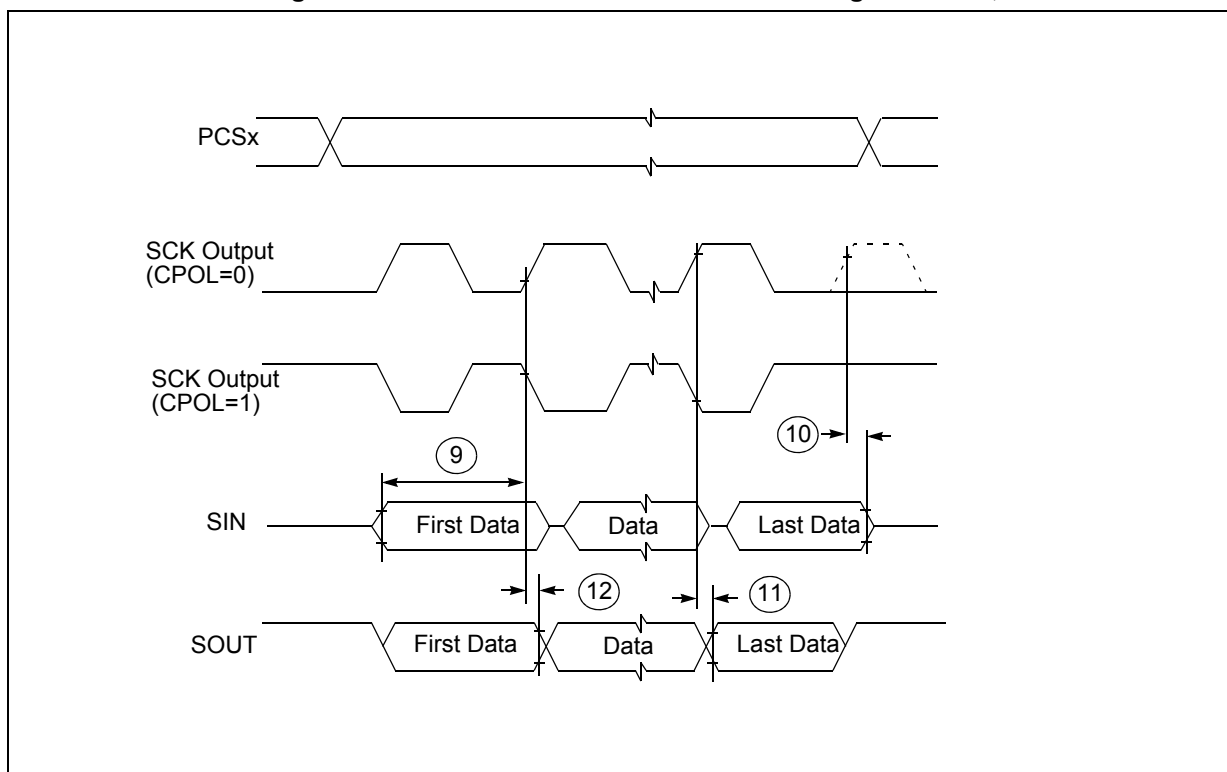
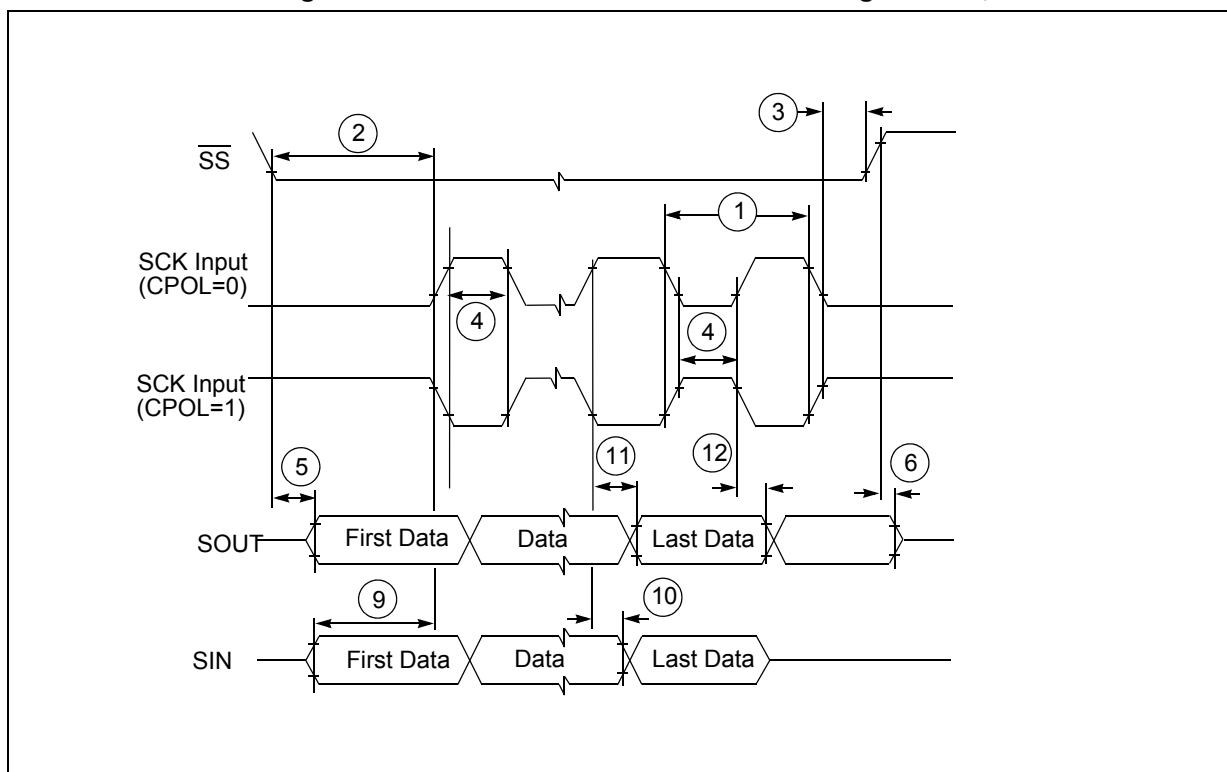
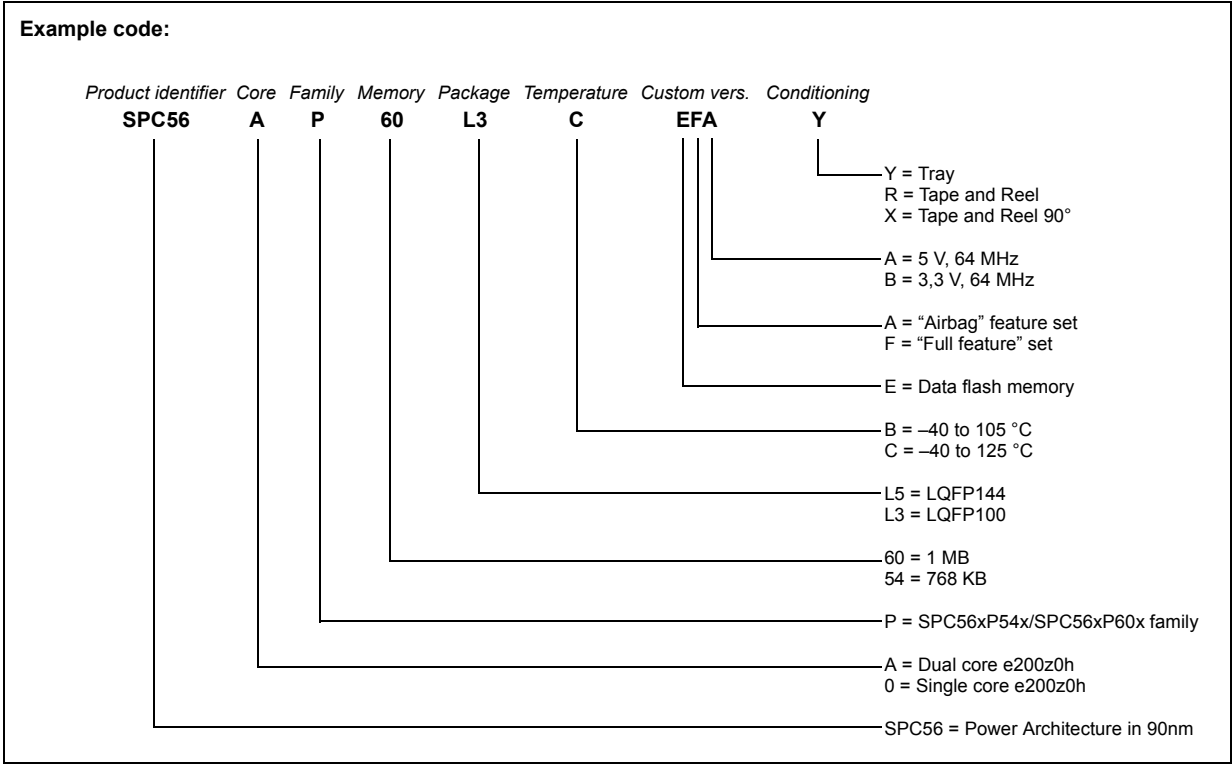


Figure 35. DSPI modified transfer format timing — slave, CPHA = 0



5 Ordering information

Figure 40. Ordering information scheme^(h)



h. Not all configurations are available on the market. Please contact your ST sales representative to get the list of orderable commercial part number.

Table 44. Document revision history (continued)

Date	Revision	Substantive changes
21-Nov-2012	4	In the cover page, replaced “64 MHz, dual issue, 32-bit CPU core complex” with “64 MHz, single issue, 32-bit CPU core complex” Table 9: Absolute maximum ratings, updated TV_{DD} entry Table 22: DC electrical characteristics (3.3 V, NVUSRO[PAD3V5V]=1): Updated conditions value of V_{OL_F} to 11 mA Updated conditions value of V_{OH_F} to – 11 mA Table 24: Peripherals supply current (5 V and 3.3 V): Replaced all occurrences of I_{DD_BV} in this table with I_{DD_HV} Replaced all occurrences of VDD_BV in this table with VDD_HV_REG. Figure 40: Ordering information scheme, fixed typo in the footnote.
18-Sep-2013	5	Updated Disclaimer.
15-Jun-2016	6	Added “AEC-Q10x qualified” in Features section. In Table 2: SPC56xP54x/SPC56xP60x device comparison added footnote “LinFlex_1 is Master Only.” related to row “LINFlex modules” Updated Table 3: SPC56xP54x/SPC56xP60x device configuration difference Figure 2: LQFP176 pinout (top view): – Changed PB[4] to TDO – Changed PB[5] to TDI – Changed pins 71,72 to NC – Changed pins 87,88 to NC In Section 1.5.27: Nexus development interface (NDI), added note “At least one TCK clock is necessary for the EVTI signal to be recognized by the MCU.” for EVTI pin. In Table 7: Pin muxing: – Replaced “PCR register” with “PCR No.” – Updated “CS3” with “CS3_4” function related to A[2] port pin – In column “I/O direction”, added “O” for “DSPI_1” peripheral – In “Functions” column related to D[12] port pin, changed DS7_1 to CS7_1